MIXED-SIGNAL LSI TEST SYSTEMS

AUTOMATIC TEST EQUIPMENT

S310 Mixed-signal LSI Test System

With high speed, high accuracy, multi-pin support, and abundant offering of analog and DC modules, the S310 is an ideal mixed LSI test system for a wide variety of analog and digital devices. This test system achieves high-speed throughput and low cost due to its higher system-wide speed, integration, and lower noise.

●Specifications
- 125/250 MHz test rate
- 512 I/O pins
- Per-Pin TG/DC
- DSP modules AFG: 16 bit/10 Msps, ADGT: 16 bit/10 Msps,
  VFG: 14 bit/250 Msps, VDGT: 14 bit/100 Msps

●Target Device
CDMA, W-CDMA, CODEC, PHS, Blue Tooth, Wireless LAN, PDC, DVD, CD-ROM, Digital audio/video

WL93δ Mixed-signal LSI Test System

The WL93 δ is a mixed tester that adds high speed, high accuracy, lower noise, and greater cost performance to the analog measuring unit of the existing WL93 α test system.

●Specifications
- 50/100 MHz test rates
- 256 I/O pins
- Per-Pin DC
- DSP modules AFG: 16 bit/10 Msps, ADGT: 16 bit/10 Msps,
  VFG: 14 bit/250 Msps, VDGT: 14 bit/100 Msps

●Target Device
CDMA, W-CDMA, CODEC, PHS, Fax-Modem, PDC, DVD, CD-ROM, Digital audio/video

WL27 Mixed-signal LSI Test System

The WL27 is a best solution mixed tester offering simultaneous testing, high-speed throughput, and superior cost performance. It covers a wide range of devices, including advanced analog LSIs and power devices, ICs for automobiles, and digital LSIs for consumer use.

●Specifications
- 20/40 MHz test rates
- 128 digital I/O, 128 PPS, Analog 64 pins
- DSP modules AFG: 16 bit/10 Msps, ADGT: 16 bit/10 Msps,
  VFG: 14 bit/250 Msps, VDGT: 14 bit/100 Msps

●Target Device
Automotive, Motor drivers, MCU, Composite regulators, System LSIs

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